The 10th Workshop on Advances in Model Based Testing (A-MOST'15)

Co-located with IEEE International Conference on Software Testing, Verification and Validation (ICST'15)
April 17, 2015 in Graz, Austria

Workshop Website: http://msdl.cs.mcgill.ca/conferences/amost/

Important Dates:
Paper submission: January 30, 2015
Author notification: March 1, 2015
Camera-ready version due: March 24, 2015
Conference date: April 17, 2015

Theme and Goals: The increasing complexity of software results in new challenges for testing. Model Based Testing (MBT) continues to be an important research area, where new approaches, methods and tools make MBT techniques more deployable and useful for industry than ever. Models and different abstractions can ease comprehension of a complex system and ease test generation and automation. A-MOST has proven to be a successful workshop that brings researchers and practitioners together discussing formal and semi-formal approaches, specification formats and notations that contribute to simplifying complex aspects of a system. The goal is to bring researchers and practitioners together to discuss state of the art, practice and future prospects in MBT.

Topics of Interest: This workshop would like to encourage the submission of original papers that deal with any of the following topics, but not limited to:

- The models used in MBT
- The processes, techniques, and tools that support MBT
- Evaluation (i.e., the evaluation of software using MBT and the evaluation of MBT)
- Models for component, integration and system testing
- Product-line models
- (Hybrid) embedded system models
- Systems-of-systems models & Architectural models
- Models for orchestration and choreography of services
- Executable models, simulation and model transformations
- Environment and use models
- Non-functional models and quantitative MBT
- Model-based test generation algorithms
- Application of model checking techniques in model-based testing
- Tracing from requirements model to test models
- Performance and predictability of model-driven development
- Test model evolution during the software lifecycle
- Generation of testing-infrastructures from models
- Combinatorial approaches for MBT Statistical testing
- Estimating dependability (e.g., security, safety, reliability) using MBT
- Coverage metrics and measurements for structural and (non-)functional models
- Cost of testing, economic impact of MBT
- Empirical validation, experiences, case studies using MBT

Paper Formatting:

The submission format should not exceed 10 pages (including all text, figures, references and appendices) for research papers or up to 6 pages for short papers i.e., experience reports and position papers. There are two types of papers: research papers and short papers. Each submitted paper must conform to the IEEE two-column publication format.

Submission and Proceedings:

Full papers should be submitted before January the 30th in PDF through the easy-chair submission website at https://easychair.org/conferences/?conf=amost2015
Papers will be reviewed by at least three members of the program committee and the notification of accepted papers will be sent before February the 10th.
Accepted papers must be orally presented during the workshop to be published within ICST proceedings. Accepted papers will be published at the IEEE Digital Library.

Program Chairs:

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- Gilles Perrouin, University of Namur, Belgium

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